

**Search Notes**

Application/Control No.

10/756,776

Examiner

Phillip Nguyen

Applicant(s)/Patent under  
Reexamination

TANAKA, KOICHIRO

Art Unit

2828

**SEARCHED**

| Class | Subclass | Date | Examiner |
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**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|                                     | DATE      | EXMR |
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| EAST text search (see the printout) | 8/19/2006 | PN   |
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